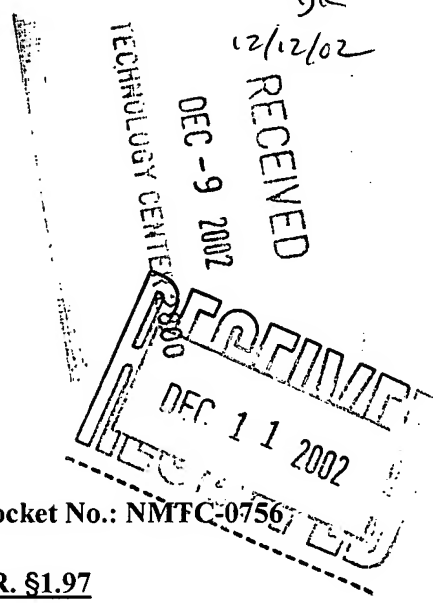




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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on December 2, 2002

Wendy Dial

(Typed or Printed Name of Person Mailing Paper or Fee)

Wendy Dial
(Signature of Person Mailing Paper or Fee)

Attorney Docket No.: NMFC-07567

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Inventor: Youping Zhang
Title: METHOD AND APPARATUS FOR CONTROLLING RIPPLING DURING OPTICAL PROXIMITY CORRECTION
Filing Date: December 12, 2001
Serial Number: 10/016,837
Group Art Unit: 2825
Examiner: To Be Assigned

Listed below or on an attached Form PTO-1449 is information known to applicant(s) and submitted pursuant to 37 C.F.R. §1.56. A copy of each listed publication and U.S. and foreign patent, except for pending U.S. applications, is being submitted herewith, along with a concise explanation of information in a foreign language, if any, pursuant to 37 C.F.R. §1.97-1.98.

Applicants respectfully request that the listed information be considered by the Examiner and be made of record in the above-identified application. If form PTO-1449 is enclosed, the Examiner is requested to initial and return it in accordance with MPEP §609.

This statement is not intended to represent that a search has been made or that the information cited in the statement is, or is considered to be, material to patentability as defined in §1.56.

X This statement qualifies under 37 C.F.R. §1.97, subsection (b) because (check all that apply):

- ☐ (1) It is being filed within 3 months of the application filing date
-- OR --
☐ (2) It is being filed within 3 months of entry of a national stage
-- OR --
X (3) It is being filed before the mail date of the first Office Action on the merits.

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— 37 C.F.R. §1.97(c). If this statement is being filed after the latest of: (1) three months beyond the filing date of a national application; (2) three months beyond the date of entry of the national stage as set forth in §1.491 in an international application; or (3) the mailing date of a first Office action on the merits, but before the mailing date of the earlier of a final office action under §1.113 or a notice of allowance under §1.311, then:

— a certification as specified in §1.97(e) is provided below; or

— a fee of \$240.00 as set forth in §1.17(p) is authorized below, enclosed, or included with the payment of other papers filed together with this statement. Please note that a check in the amount of \$240.00 is enclosed in payment.

— 37 C.F.R. §1.97(d). If this statement is being filed after the mailing date of the earlier of a final office action under §1.113 or a notice of allowance under §1.311, but before payment of the issue fee, then:

A. a certification as specified in §1.97(e) is completed below; and

B. a petition under 37 C.F.R. §1.97(d) requesting consideration of this statement is submitted herewith; and


C. a fee of \$130.00 as set forth in §1.17(i)(1) is authorized below, enclosed, or included with the payment of other papers filed together with this statement.

— Statement under 37 C.F.R. §1.97(e) - I hereby certify that either: each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign patent application not more than three months prior to the filing of the information disclosure statement; or no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign patent application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in section 1.56(c) more than three months prior to the filing of the information disclosure statement.

Signature: _____
A. Richard Park (Reg. No. 41,241)

Date

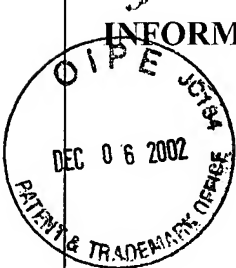
Respectfully submitted,

By: 
A. Richard Park
Reg. No. 41,241

PARK, VAUGHAN & FLEMING LLP
508 Second Street, Suite 201
Davis, CA 95616
(530) 759-1661

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Date: December 2, 2002

|  <p>INFORMATION DISCLOSURE CITATION</p> <p>PTO-1449</p> | | | Atty. Docket No. NMTC-0756 | | Serial No. 10/016,837 | |
|---|-----------------|------------|--------------------------------------|-------|---------------------------------|----------------|
| | | | Applicant ZHANG, Youping | | Group 2825 | |
| | | | Filing Date 12/12/2001 | | | |
| U.S. PATENT DOCUMENTS | | | | | | |
| EXAMINER'S INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE |
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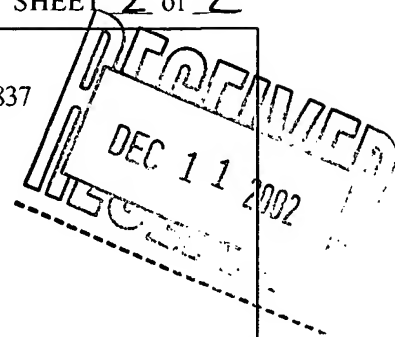
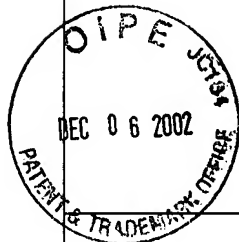
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|---|---|--------------------------------------|---------------------------------|
| INFORMATION DISCLOSURE CITATION PTO-1449 | | Atty. Docket No. NMTC-0756 | Serial No. 10/016,837 |
| | | Applicant ZHANG, Youping | Group 2825 |
| | | Filing Date 12/12/2001 | |
| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) | | | |
| EXAMINER'S INITIALS | CITATION | | |
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